





SID4-UV

COST-EFFECTIVE, HIGH RESOLUTION UV WAVEFRONT SENSOR

Bringing high-resolution wavefront sensing as low as 250 nm, SID4-UV is perfectly suited for UV optics testing, UV laser characterization (used in lithography or semiconductor applications) and surface inspection of lenses and wafers.

APPLICATIONS: Laser industry | Semiconductor | Astronomy | Aerospace | AR/VR

| SPECIFICATIONS | |
|--------------------------------|----------------------------------|
| Wavelength range | 250 - 400 nm |
| Aperture dimensions | 7.4 x 7.4 mm ² |
| Phase spatial resolution | 29.6 μm |
| Phase & Intensity sampling | 250 x 250 |
| Resolution (Phase) | 2 nm RMS |
| Accuracy (Absolute) | 10 nm RMS |
| Frame rate | 30 fps |
| Real-time processing frequency | 2 fps (full resolution)* |
| Interface | Giga Ethernet |
| Dimensions | 78 x 88.1 x 71.1 mm ³ |
| Weight | ~ 575g |
| | |



* with SID4 software

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